1. Record Nr. UNIORUON00406051

Autore	Mingione, Enzo
Titolo	Occupazione, qualificazione e mercato del lavoro : una ricerca di qualificazione e l'occupazione impiegatizia in Italia oggi / Enzo Mingione, Francesca Zajczyk ; a cura di Istituto di sociologia. Università degli Studi di Milano
Pubbl/distr/stampa	Milano, : Sapere edizioni, 1974
Descrizione fisica	207 p. ; 20 cm.
Altri autori (Persone)	Zajczyk, Francesca
Soggetti	Sociologia del lavoro
Lingua di pubblicazione	Italiano
Formato	Materiale a stampa
Livello bibliografico	Monografia

2. Record Nr. UNINA9910299666303321

Titolo	Circuit Design for Reliability / / edited by Ricardo Reis, Yu Cao, Gilson Wirth
Pubbl/distr/stampa	New York, NY : , : Springer New York : , : Imprint : Springer, , 2015
ISBN	1-4614-4078-5
Edizione	[1st ed. 2015.]
Descrizione fisica	1 online resource (271 p.)
Disciplina	620 620.00420285 621.3815 658.56
Soggetti	Electronic circuits Security systems Computer-aided engineering Electronic Circuits and Systems Security Science and Technology Computer-Aided Engineering (CAD, CAE) and Design
Lingua di pubblicazione	Inglese

Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references at the end of each chapters.
Nota di contenuto	Introduction -- Recent Trends in Bias Temperature Instability -- Charge trapping phenomena in MOSFETS: From Noise to Bias Temperature Instability -- Atomistic Simulations on Reliability -- On-chip characterization of statistical device degradation -- Circuit Resilience Roadmap -- Layout Aware Electromigration Analysis of Power/Ground Networks -- Power-Gating for Leakage Control and Beyond -- Soft Error Rate and Fault Tolerance Techniques for FPGAs.
Sommario/riassunto	This book presents physical understanding, modeling and simulation, on-chip characterization, layout solutions, and design techniques that are effective to enhance the reliability of various circuit units. The authors provide readers with techniques for state of the art and future technologies, ranging from technology modeling, fault detection and analysis, circuit hardening, and reliability management. Provides comprehensive review on various reliability mechanisms at sub-45nm nodes; Describes practical modeling and characterization techniques for reliability; Includes thorough presentation of robust design techniques for major VLSI design units; Promotes physical understanding with first-principle simulations.